

Resource Summary Report

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JEOL JEM-120i Transmission Electron Microscope

RRID:SCR_028383

Type: Tool

Proper Citation

JEOL JEM-120i Transmission Electron Microscope (RRID:SCR_028383)

Resource Information

URL: <https://www.jeol.com/products/scientific/tem/JEM-120i.php>

Proper Citation: JEOL JEM-120i Transmission Electron Microscope (RRID:SCR_028383)

Description: Modern 120 kV Transmission Electron Microscope (TEM) designed for high-throughput screening and ease of use in biological, materials science, and nanotechnology research. Resolution: Achieves 0.14 nm (High Resolution) to 0.2 nm (High Contrast) lattice resolution. Magnification: Range from x50 to x1,500,000 (HR) or x1,200,000 (HC). Imaging System: Includes a 4-megapixel, high-speed, high-sensitivity JEOL CMOS camera (NeoView) as standard, with options for a 19-megapixel (SightSKY) camera. Versatile Applications: It can be used for cryo-TEM screening, material sciences, and high-throughput asbestos analysis.

Synonyms: JEOL JEM 120i TEM

Resource Type: instrument resource

Keywords: Transmission Electron Microscope (TEM), microscope, electron microscope, cryo-TEM screening, material sciences, high-throughput asbestos analysis,

Specification URL: https://raw.githubusercontent.com/SciCrunch/RRID-Instruments/refs/heads/main/PDF/SCR_028383.pdf

Resource Name: JEOL JEM-120i Transmission Electron Microscope

Resource ID: SCR_028383

Alternate IDs: Model_Number_JEOL_JEM_120i

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Record Last Update: 20260912T200549+0000

Ratings and Alerts

No rating or validation information has been found for JEOL JEM-120i Transmission Electron Microscope.

No alerts have been found for JEOL JEM-120i Transmission Electron Microscope.

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We have not found any literature mentions for this resource.